							REVISI	ONS										
LTR		DESCRIPTION									DATE (YR-MO-DA)			DA)	APPROVED			
А	Change	es in accorda	ance with	NOR 5962	-R118-9	2.					92-02-04				M. A. Frye			
В	Change	Changes in accordance with NOR 5962-R198-93							93-07-13			M. A. Frye						
С		 Incorporate revisions A and B N.O.R.'s. Update drawing to currer Editorial changes throughout drw 						rrent re	quirem	ents.		01-0)8-15		F	Raymond Monnin		
D	Corrected generic number paragraph 1.2.1drw											02-1	10-04		F	Raymon	d Monr	nin
THE ORIGINAL REV	. FIRST P	AGE OF TH	IS DRAV	WING HAS	BEENI	REPLA	CED											
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OF SHEETS			SHEE	Т	1	2	3	4	5	6	7	8	9	10	11	12		
PMIC N/A			PREPA	ARED BY							•							•
				Larry T	. Gaude	er		DEFENSE SUPPLY CENTER COLUMBUS										
	NDARD		CHEC	KED BY										HIO		5		
MICRC DRA		JIT		Ray	Monnin						http)://WV	vw.ds	cc.dl	a.mil			
			APPRO	OVED BY														
THIS DRAWING IS AVAILABLE FOR USE BY ALL DEPARTMENTS		L		Micha	el A. Fry	e								BIPOL QUAI		ADVA PLE	NCE	D
	AND AGENCIES OF THE			ING APPR	OVAL D	ATE					AL LI	NE R	ECEI	VER,	MON	NOLIT	ГНІС	
DEPARTMENT OF DEFENSE		FENSE		88-	11-17			SILICON										
AM	SC N/A		REVIS	ION LEVEI					ZE		GE CC				5962.	-8864	9	
					D				4		67268	3		•		5504	-	
					SHEET 1 OF 12													

DSCC FORM 2233 APR 97

DISTRIBUTION STATEMENT A. Approved for public release; distribution is unlimited.

1.1 <u>Scope</u>. This drawing describes device requirements for MIL-STD-883 compliant, non-JAN class level B microcircuits in accordance with MIL-PRF-38535, appendix A.

1.2 Part or Identifying Number (PIN). The complete PIN is as shown in the following example:



2. APPLICABLE DOCUMENTS

2.1 <u>Government specification, standards, and handbooks</u>. The following specification, standards, and handbooks form a part of this drawing to the extent specified herein. Unless otherwise specified, the issues of these documents are those listed in the issue of the Department of Defense Index of Specifications and Standards (DoDISS) and supplement thereto, cited in the solicitation.

SPECIFICATION

DEPARTMENT OF DEFENSE

MIL-PRF-38535 - Integrated Circuits, Manufacturing, General Specification for.

STANDARDS

DEPARTMENT OF DEFENSE

MIL-STD-883	-	Test Method Standard Microcircuits.
MIL-STD-1835	-	Interface Standard Electronic Component Case Outlines.

HANDBOOKS

DEPARTMENT OF DEFENSE

MIL-HDBK-103 -	List of Standard Microcircuit Drawings.
MIL-HDBK-780 -	Standard Microcircuit Drawings.

(Unless otherwise indicated, copies of the specification, standards, and handbooks are available from the Standardization Document Order Desk, 700 Robbins Avenue, Building 4D, Philadelphia, PA 19111-5094.)

2.2 <u>Order of precedence</u>. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing takes precedence. Nothing in this document, however, supersedes applicable laws and regulations unless a specific exemption has been obtained.

3. REQUIREMENTS

3.1 <u>Item requirements</u>. The individual item requirements shall be in accordance with MIL-PRF-38535, appendix A for non-JAN class level B devices and as specified herein. Product built to this drawing that is produced by a Qualified Manufacturer Listing (QML) certified and qualified manufacturer or a manufacturer who has been granted transitional certification to MIL-PRF-38535 may be processed as QML product in accordance with the manufacturers approved program plan and qualifying activity approval in accordance with MIL-PRF-38535. This QML flow as documented in the Quality Management (QM) plan may make modifications to the requirements herein. These modifications shall not affect form, fit, or function of the device. These modifications shall not affect the PIN as described herein. A "Q" or "QML" certification mark in accordance with MIL-PRF-38535 is required to identify when the QML flow option is used.

3.2 <u>Design, construction, and physical dimensions</u>. The design, construction, and physical dimensions shall be as specified in MIL-PRF-38535, appendix A and herein.

3.2.1 <u>Case outlines</u>. The case outlines shall be in accordance with 1.2.2 herein.

3.2.2 <u>Terminal connections</u>. The terminal connections shall be as specified on figure 1.

- 3.2.3 <u>Truth table</u>. The truth table shall be as specified on figure 2.
- 3.2.4 Logic diagrams. The logic diagrams shall be as specified on figure 3.

3.2.5 Test circuit and switching waveforms. Test circuit and switching waveforms shall be as specified on figure 4.

STANDARD MICROCIRCUIT DRAWING	SIZE A		5962-88649
DEFENSE SUPPLY CENTER COLUMBUS		REVISION LEVEL	SHEET
COLUMBUS, OHIO 43216-5000		D	3

3.3 <u>Electrical performance characteristics</u>. Unless otherwise specified herein, the electrical performance characteristics are as specified in table I and shall apply over the full case operating temperature range.

3.4 <u>Electrical test requirements</u>. The electrical test requirements shall be the subgroups specified in table II. The electrical tests for each subgroup are described in table I.

3.5 <u>Marking</u>. Marking shall be in accordance with MIL-PRF-38535, appendix A. The part shall be marked with the PIN listed in 1.2 herein. In addition, the manufacturer's PIN may also be marked as listed in MIL-HDBK-103 (see 6.6 herein). For packages where marking of the entire SMD PIN number is not feasible due to space limitations, the manufacturer has the option of not marking the "5962-" on the device.

3.5.1 <u>Certification/compliance mark</u>. A compliance indicator "C" shall be marked on all non-JAN devices built in compliance to MIL-PRF-38535, appendix A. The compliance indicator "C" shall be replaced with a "Q" or "QML" certification mark in accordance with MIL-PRF-38535 to identify when the QML flow option is used.

3.6 <u>Certificate of compliance</u>. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in MIL-HDBK-103 (see 6.6 herein). The certificate of compliance submitted to DSCC-VA prior to listing as an approved source of supply shall affirm that the manufacturer's product meets the requirements of MIL-PRF-38535, appendix A and the requirements herein.

3.7 <u>Certificate of conformance</u>. A certificate of conformance as required in MIL-PRF-38535, appendix A shall be provided with each lot of microcircuits delivered to this drawing.

3.8 <u>Notification of change</u>. Notification of change to DSCC-VA shall be required in accordance with MIL-PRF-38535, appendix A.

3.9 <u>Verification and review</u>. DSCC, DSCC's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.

4. QUALITY ASSURANCE PROVISIONS

4.1 <u>Sampling and inspection</u>. Sampling and inspection procedures shall be in accordance with MIL-PRF-38535, appendix A.

4.2 <u>Screening</u>. Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:

- a. Burn-in test, method 1015 of MIL-STD-883.
 - (1) Test condition B or D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to the preparing or acquiring activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in test method 1015 of MIL-STD-883.
 - (2) $T_A = +125^{\circ}C$, minimum.
- b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.

STANDARD MICROCIRCUIT DRAWING	SIZE A		5962-88649
DEFENSE SUPPLY CENTER COLUMBUS		REVISION LEVEL	SHEET
COLUMBUS, OHIO 43216-5000		D	4

	Т	TABLE I. Electrical	performance ch	aracteristics.				
Test	Symbol	$\begin{array}{c} \text{Condit}\\ \text{-55}^\circ\text{C} \leq \text{T}_\text{C}\\ \text{4.5} \ \text{V} \leq \text{V}_\text{C} \end{array}$	≤+125°C	Group A subgroups	Device type	Lin	nits	Unit
	_	unless otherwise specified		ļ	<u> </u> !	Min	Max	
Positive-going threshold voltage	V _T +			1, 2, 3	All		200	mV
Negative-going threshold voltage	V _T -			1, 2, 3	All	-200		mV
Enable input clamp voltage	V _{IC}	V_{CC} = 4.5 V, I _{IN} =	18 mA	1, 2, 3	All		-1.5	V
High level output voltage	V _{OH}		$\label{eq:V_CC} \begin{array}{l} V_{CC} = 4.5 \ V, \ V_{ID} = 200 \ mV, \\ I_{OH} = -0.4 \ mA \ V_{IL} = 0.8 \ V \end{array}$		All	2.5		V
Low level output voltage	V _{OL}	$V_{ID} = -200 \text{ mV},$ $V_{IH} = 2.0 \text{ V},$	I _{OL} = 8 mA	1, 2, 3	All		0.45	V
		$\begin{array}{l} V_{IL} = 0.8 \; V, \\ V_{CC} = 4.5 \; V \end{array}$	I _{OL} = 16 mA				0.50	
High impedance state output current	I _{OZ}	$V_{CC} = 5.5 V,$	$V_{ID} = -3.0 V,$ $V_{OUT} = 2.7 V$	1, 2, 3	All		20	μΑ
		V _{IL} = 0.8 V	V _{ID} = 3.0 V, V _{OUT} = 0.5 V				-20	
Line input current	h	Other input	$\begin{array}{l} V_{CC} = 4.5 \ V, \\ V_{IN} = 15 \ V \end{array}$	1, 2, 3	All		1.2	mA
		at 0.0 V	$V_{CC} = 5.5 V,$ $V_{IN} = -15 V$				-1.7	
High level enable input current	IIH	V _{CC} = 5.5 V	V _{IH} = 2.7 V	1, 2, 3	All		20	μΑ
			V _{IH} = 5.5 V				100	
Low level enable input		$V_{CC} = 5.5 \text{ V}, V_{IL} = 0.4 \text{ V}$		1, 2, 3	All		-100	μΑ
Input resistance	Rı	V _{CC} = 5.5 V		1, 2, 3	All	12		kΩ
				1, 2, 3	All	-15	-130	mA
Supply current	I _{CC}	$V_{CC} = 5.5 V$, outp	puts disabled	1, 2, 3	All		35	mA
Functional tests		See 4.3.1c		7, 8	All			

See footnotes at end of table.

STANDARD MICROCIRCUIT DRAWING	SIZE A		5962-88649
DEFENSE SUPPLY CENTER COLUMBUS		REVISION LEVEL	SHEET
COLUMBUS, OHIO 43216-5000		D	5

	TABLE	I. Electrical performance chara	<u>cteristics</u> - con	tinued.				
Test	Symbol	$Conditions \\ -55^{\circ}C \leq T_C \leq +125^{\circ}C \\ \text{unless otherwise specified}$	Group A subgroups	Device type	Limits		Unit	
					Min	Max		
Propagation delay time,	t _{PLH}		9	All		25	ns	
A, B to Y		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V},$ $V_{ID} = -1.5 \text{ V to } 1.5 \text{ V},$	10, 11	All		35	ns	
	t _{PHL}	$C_L = 15 \text{ pF}$, See figure 4 <u>2</u> /	9	All		23	ns	
		=	10, 11	All		34	ns	
Output enable time,	t _{PZH}		9	All		28	ns	
A, B to Y		$V_{CC} = 4.5 V \text{ to } 5.5 V,$	10, 11	All		40	ns	
	t _{PZL}		9	All		27	ns	
			10, 11	All		40	ns	
Output disable time,	t _{PHZ}	$C_L = 15 \text{ pF}$, See figure 4 <u>2</u> /	9	All		30	ns	
A, B to Y			10, 11	All		40	ns	
	t _{PLZ}		9	All		24	ns	
			10, 11	All		35	ns	

1/ Not more than one output should be shorted at one time, and the duration of the short circuit condition shall not exceed one second.

 $\underline{2}/$ Vendor may test with V_{CC} = 5.0 V but must guarantee the 4.5 V to 5.5 V limits.

STANDARD MICROCIRCUIT DRAWING	SIZE A		5962-88649
DEFENSE SUPPLY CENTER COLUMBUS COLUMBUS, OHIO 43216-5000		REVISION LEVEL D	SHEET 6

Device type	01	l
Case outlines	E and F	2
Terminal number	Terminal	symbol
1	1B	NC
2	1A	1B
3	1Y	1A
4	1, 2EN	1Y
5	2Y	1, 2EN
6	2A	NC
7	2B	2Y
8	GND	2A
9	3B	2B
10	ЗA	GND
11	3Y	NC
12	3, 4EN	3B
13	4Y	ЗA
14	4A	3Y
15	4B	3, 4EN
16	V _{CC}	NC
17		4Y
18		4A
19		4B
20		V _{cc}

NC = No internal connection

FIGURE 1.	Terminal	connections.

Differential input	Enables	Output
A - B	EN	Y
$V_{ID} \geq 0.2 \ V$	Н	Н
-0.2 V < V_{ID} < 0.2 V	Н	Ι
$V_{ID} \leq$ -0.2 V	Н	L
Х	L	Z

H = High level voltage L = Low level voltage

X = Irrelevant I = Indeterminate

Z = High impedance (off)

FIGURE 2. Truth table.

STANDARD MICROCIRCUIT DRAWING	SIZE A		5962-88649
DEFENSE SUPPLY CENTER COLUMBUS		REVISION LEVEL	SHEET
COLUMBUS, OHIO 43216-5000		D	7







MIL-STD-883 test requirements	Subgroups
	(in accordance with
	MIL-STD-883, method 5005,
	table I)
Interim electrical parameters	
(method 5004)	
Final electrical test parameters	1*. 2. 3. 7. 8. 9
(method 5004)	1, 2, 3, 7, 8, 9
Group A test requirements	1, 2, 3, 7, 8, 9, 10**, 11**
(method 5005)	1, 2, 3, 7, 6, 9, 10 , 11
Groups C and D end-point	
electrical parameters	1, 2, 3
(method 5005)	

TABLE II. Electrical test requirements.

* PDA applies to subgroup 1.

** Subgroups 10 and 11, if not tested, shall be guaranteed to the limits specified in table I.

4.3 <u>Quality conformance inspection</u>. Quality conformance inspection shall be in accordance with method 5005 of MIL-STD-883 including groups A, B, C, and D inspections. The following additional criteria shall apply.

4.3.1 Group A inspection.

- a. Tests shall be as specified in table II herein.
- b. Subgroups 4, 5, and 6 in table I, method 5005 of MIL-STD-883 shall be omitted.
- c. Subgroups 7 and 8 shall include verification of the truth table as specified on figure 2 herein.

4.3.2 Groups C and D inspections.

- a. End-point electrical parameters shall be as specified in table II herein.
- b. Steady-state life test conditions, method 1005 of MIL-STD-883.
 - (1) Test condition B or D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to the preparing or acquiring activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in test method 1005 of MIL-STD-883.
 - (2) $T_A = +125^{\circ}C$, minimum.
 - (3) Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.

STANDARD MICROCIRCUIT DRAWING	SIZE A		5962-88649
DEFENSE SUPPLY CENTER COLUMBUS		REVISION LEVEL	SHEET
COLUMBUS, OHIO 43216-5000		D	11

5. PACKAGING

5.1 <u>Packaging requirements</u>. The requirements for packaging shall be in accordance with MIL-PRF-38535, appendix A.

6. NOTES

6.1 <u>Intended use</u>. Microcircuits conforming to this drawing are intended for use for Government microcircuit applications (original equipment), design applications, and logistics purposes.

6.2 <u>Replaceability</u>. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.

6.3 <u>Configuration control of SMD's</u>. All proposed changes to existing SMD's will be coordinated with the users of record for the individual documents. This coordination will be accomplished using DD Form 1692, Engineering Change Proposal.

6.4 <u>Record of users</u>. Military and industrial users shall inform Defense Supply Center Columbus when a system application requires configuration control and the applicable SMD. DSCC will maintain a record of users and this list will be used for coordination and distribution of changes to the drawings. Users of drawings covering microelectronics devices (FSC 5962) should contact DSCC-VA, telephone (614) 692-0544.

6.5 <u>Comments</u>. Comments on this drawing should be directed to DSCC-VA, Columbus, Ohio 43216-5000, or telephone (614) 692-0547.

6.6 <u>Approved sources of supply</u>. Approved sources of supply are listed in MIL-HDBK-103. The vendors listed in MIL-HDBK-103 have agreed to this drawing and a certificate of compliance (see 3.6 herein) has been submitted to and accepted by DSCC-VA.

STANDARD MICROCIRCUIT DRAWING	SIZE A		5962-88649
DEFENSE SUPPLY CENTER COLUMBUS COLUMBUS, OHIO 43216-5000		REVISION LEVEL D	SHEET 12

STANDARD MICROCIRCUIT DRAWING BULLETIN

DATE: 02-10-04

Approved sources of supply for SMD 5962-88649 are listed below for immediate acquisition information only and shall be added to MIL-HDBK-103 and QML-38535 during the next revision. MIL-HDBK-103 and QML-38535 will be revised to include the addition or deletion of sources. The vendors listed below have agreed to this drawing and a certificate of compliance has been submitted to and accepted by DSCC-VA. This bulletin is superseded by the next dated revision of MIL-HDBK-103 and QML-38535.

1		
Standard	Vendor	Vendor
microcircuit drawing	CAGE	similar
PIN <u>1</u> /	number	PIN <u>2</u> /
5962-8864901EA	<u>3</u> /	SNJ55ALS195J
5962-8864901FA	<u>3</u> /	SNJ55ALS195W
5962-88649012A	<u>3</u> /	SNJ55ALS195FK

- 1/ The lead finish shown for each PIN representing a hermetic package is the most readily available from the manufacturer listed for that part. If the desired lead finish is not listed contact the vendor to determine its availability.
- <u>2</u>/ <u>Caution</u>. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.
- 3/ No approved source.

Vendor CAGE <u>number</u> Vendor name and address

The information contained herein is disseminated for convenience only and the Government assumes no liability whatsoever for any inaccuracies in the information bulletin.